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6.DAE & Probe Calibration certificate

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst S Service suisse d'étalonnage С Servizio svizzero di taratura Swiss Calibration Service

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Client

SGS (Auden)

Certificate No: DAE4-547 Oct07

Accreditation No.: SCS 108

Object	DAE4 - SD 000 D04 BA - SN: 547					
Calibration procedure(s)	QA CAL-06.v12 Calibration procedure for the data acquisition electronics (DAE)					
alibration date:	October 1, 2007					
condition of the calibrated item	In Tolerance					
		onal standards, which realize the physical uni obability are given on the following pages an				
Il calibrations have been conducte	ed in the closed laboratory	facility: environment temperature (22 ± 3)°C	C and humidity < 70%.			
Calibration Equipment used (M&TE	critical for calibration)					
	critical for calibration)	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration			
rimary Standards uke Process Calibrator Type 702	ID# SN: 6295803	13-Oct-06 (Elcal AG, No: 5492)	Scheduled Calibration Oct-07			
rimary Standards luke Process Calibrator Type 702	ID#					
rimary Standards uke Process Calibrator Type 702 eithley Multimeter Type 2001	ID# SN: 6295803	13-Oct-06 (Elcal AG, No: 5492) 03-Oct-06 (Elcal AG, No: 5478)	Oct-07 Oct-07			
rrimary Standards luke Process Calibrator Type 702 eithley Multimeter Type 2001 econdary Standards	ID# SN: 6295803 SN: 0810278	13-Oct-06 (Elcal AG, No: 5492) 03-Oct-06 (Elcal AG, No: 5478) Check Date (in house)	Oct-07			
rimary Standards luke Process Calibrator Type 702 eithley Multimeter Type 2001 econdary Standards	ID # SN: 6295803 SN: 0810278	13-Oct-06 (Elcal AG, No: 5492) 03-Oct-06 (Elcal AG, No: 5478) Check Date (in house)	Oct-07 Oct-07 Scheduled Check			
rimary Standards luke Process Calibrator Type 702 eithley Multimeter Type 2001 econdary Standards	ID # SN: 6295803 SN: 0810278	13-Oct-06 (Elcal AG, No: 5492) 03-Oct-06 (Elcal AG, No: 5478) Check Date (in house)	Oct-07 Oct-07 Scheduled Check			
rimary Standards uke Process Calibrator Type 702 eithley Multimeter Type 2001 econdary Standards	ID # SN: 6295803 SN: 0810278 ID # SE UMS 006 AB 1004	13-Oct-06 (Elcal AG, No: 5492) 03-Oct-06 (Elcal AG, No: 5478) Check Date (in house) 25-Jun-07 (SPEAG, in house check)	Oct-07 Oct-07 Scheduled Check In house check Jun-08			
rimary Standards luke Process Calibrator Type 702 eithley Multimeter Type 2001 econdary Standards alibrator Box V1.1	ID # SN: 6295803 SN: 0810278	13-Oct-06 (Elcal AG, No: 5492) 03-Oct-06 (Elcal AG, No: 5478) Check Date (in house)	Oct-07 Oct-07 Scheduled Check In house check Jun-08			
Calibration Equipment used (M&TE Primary Standards Fluke Process Calibrator Type 702 Geithley Multimeter Type 2001 Secondary Standards Calibrator Box V1.1	ID # SN: 6295803 SN: 0810278 ID # SE UMS 006 AB 1004 Name	13-Oct-06 (Elcal AG, No: 5492) 03-Oct-06 (Elcal AG, No: 5478) Check Date (in house) 25-Jun-07 (SPEAG, in house check) Function	Oct-07 Oct-07 Scheduled Check In house check Jun-08			

Certificate No: DAE4-547_Oct07

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Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





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Accreditation No.: SCS 108

SGS (Auden) Certificate No: EX3-3526_Aug07 **CALIBRATION CERTIFICATE** EX3DV3 - SN:3526 Object QA CAL-01.v6 Calibration procedure(s) Calibration procedure for dosimetric E-field probes August 29, 2007 Calibration date: In Tolerance Condition of the calibrated item This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate. All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%. Calibration Equipment used (M&TE critical for calibration) **Primary Standards** ID# Cal Date (Calibrated by, Certificate No.) Scheduled Calibration Power meter E4419B GB41293874 29-Mar-07 (METAS, No. 217-00670) Mar-08 Power sensor E4412A MY41495277 29-Mar-07 (METAS, No. 217-00670) Mar-08 Power sensor E4412A MY41498087 29-Mar-07 (METAS, No. 217-00670) Mar-08 Reference 3 dB Attenuator SN: S5054 (3c) 8-Aug-07 (METAS, No. 217-00719) Aug-08 Reference 20 dB Attenuator SN: S5086 (20b) 29-Mar-07 (METAS, No. 217-00671) Mar-08 Reference 30 dB Attenuator SN: S5129 (30b) 8-Aug-07 (METAS, No. 217-00720) Aug-08 Reference Probe ES3DV2 SN: 3013 4-Jan-07 (SPEAG, No. ES3-3013_Jan07) Jan-08 DAE4 20-Apr-07 (SPEAG, No. DAE4-654_Apr07) Apr-08 Secondary Standards ID# Check Date (in house) Scheduled Check US3642U01700 RF generator HP 8648C 4-Aug-99 (SPEAG, in house check Nov-05) In house check: Nov-07 Network Analyzer HP 8753E US37390585 18-Oct-01 (SPEAG, in house check Oct-06) In house check: Oct-07 Signature Calibrated by: Katja Pokovic Technical Manager Niels Kuster Approved by: Quality Manager Issued: August 29, 2007 This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Certificate No: EX3-3526 Aug07

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Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étalonnage C Servizio svizzero di taratura **Swiss Calibration Service**

Accreditation No.: SCS 108

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Glossary:

DCP

tissue simulating liquid NORMx,y,z ConF

sensitivity in free space sensitivity in TSL / NORMx,y,z diode compression point

Polarization φ Polarization 9 φ rotation around probe axis

9 rotation around an axis that is in the plane normal to probe axis (at

measurement center), i.e., 9 = 0 is normal to probe axis

Calibration is Performed According to the Following Standards:

- a) IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- b) IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300 MHz to 3 GHz)", February 2005

Methods Applied and Interpretation of Parameters:

- *NORMx,v,z*: Assessed for E-field polarization $\vartheta = 0$ (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide). NORMx,y,z are only intermediate values, i.e., the uncertainties of NORMx,y,z does not effect the E²-field uncertainty inside TSL (see below *ConvF*).
- $NORM(f)x,y,z = NORMx,y,z * frequency_response$ (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of ConvF.
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency nor media.
- ConvF and Boundary Effect Parameters: Assessed in flat phantom using E-field (or Temperature Transfer Standard for f ≤ 800 MHz) and inside waveguide using analytical field distributions based on power measurements for f > 800 MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORMx,y,z * ConvF whereby the uncertainty corresponds to that given for ConvF. A frequency dependent ConvF is used in DASY version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- Spherical isotropy (3D deviation from isotropy): in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.

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EX3DV3 SN:3526

August 29, 2007

Probe EX3DV3

SN:3526

Manufactured: Last calibrated: March 19, 2004 August 25, 2006 August 29, 2007

Recalibrated:

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)

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EX3DV3 SN:3526

August 29, 2007

DASY - Parameters of Probe: EX3DV3 SN:3526

Sensitivity in Fre	Diode Compression ^E			
NormX	0.991 ± 10.1%	$\mu V/(V/m)^2$	DCP X	97 mV
NormY	0.807 ± 10.1%	$\mu V/(V/m)^2$	DCP Y	96 mV
NormZ	0.876 ± 10.1%	$\mu V/(V/m)^2$	DCP Z	97 mV

Sensitivity in Tissue Simulating Liquid (Conversion Factors)

Please see Page 8.

Boundary Effect

TSL	900 MHz	Typical SAR	gradient: 5 % per mm

Sensor Cente	r to Phantom Surface Distance	2.0 mm	3.0 mm	
SAR _{be} [%]	Without Correction Algorithm	1.5	0.5	
SAR _{be} [%]	With Correction Algorithm	0.3	0.4	

TSL 1810 MHz Typical SAR gradient: 10 % per mm

Sensor Cente	r to Phantom Surface Distance	2.0 mm	3.0 mm	
SAR _{be} [%]	Without Correction Algorithm	3.0	1.5	
SAR _{be} [%]	With Correction Algorithm	0.2	0.1	

Sensor Offset

Probe Tip to Sensor Center 1.0 mm

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

 $^{^{\}rm A}$ The uncertainties of NormX,Y,Z do not affect the E $^{\rm 2}$ -field uncertainty inside TSL (see Page 8).

⁸ Numerical linearization parameter: uncertainty not required.

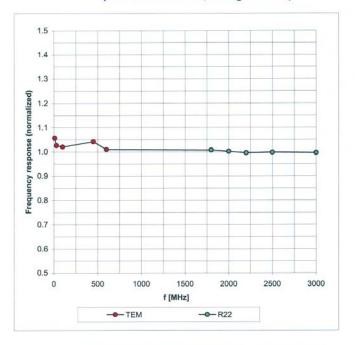
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Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)



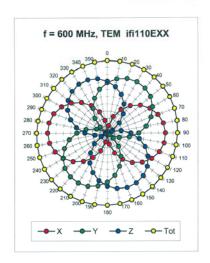
Uncertainty of Frequency Response of E-field: ± 6.3% (k=2)

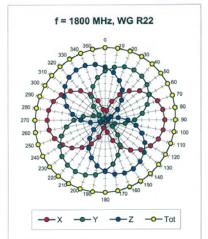
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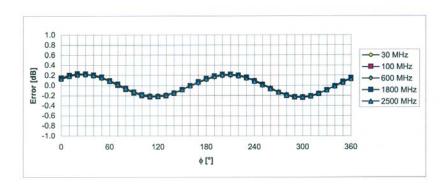
EX3DV3 SN:3526

August 29, 2007

Receiving Pattern (ϕ), $\vartheta = 0^{\circ}$







Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

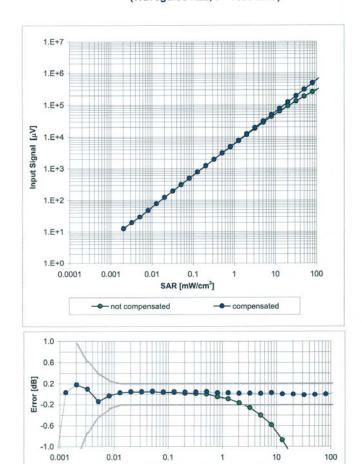
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August 29, 2007

Dynamic Range f(SAR_{head})

(Waveguide R22, f = 1800 MHz)



Uncertainty of Linearity Assessment: ± 0.6% (k=2)

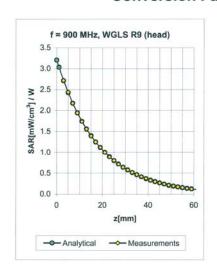
SAR [mW/cm³]

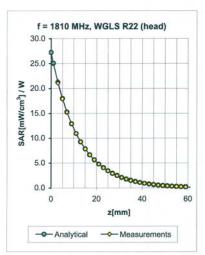
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EX3DV3 SN:3526

August 29, 2007

Conversion Factor Assessment





f [MHz]	Validity [MHz] ^C	TSL	Permittivity	Conductivity	Alpha	Depth	ConvF	Uncertainty
900	± 50 / ± 100	Head	41.5 ± 5%	0.97 ± 5%	0.50	0.80	11.48	± 11.0% (k=2)
1810	± 50 / ± 100	Head	40.0 ± 5%	1.40 ± 5%	0.15	1.32	9.30	± 11.0% (k=2)
1950	± 50 / ± 100	Head	40.0 ± 5%	1.40 ± 5%	0.22	1.01	8.91	± 11.0% (k=2)
2450	± 50 / ± 100	Head	39.2 ± 5%	1.80 ± 5%	0.34	1.00	8.42	± 11.8% (k=2)
900	± 50 / ± 100	Body	55.0 ± 5%	1.05 ± 5%	0.50	0.80	10.93	± 11.0% (k=2)
1810	± 50 / ± 100	Body	$53.3 \pm 5\%$	$1.52 \pm 5\%$	0.16	1.28	9.04	± 11.0% (k=2)
1950	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.15	1.43	8.67	± 11.0% (k=2)
2450	± 50 / ± 100	Body	52.7 ± 5%	$1.95 \pm 5\%$	0.38	1.00	8.08	± 11.8% (k=2)

 $^{^{\}mathrm{C}}$ The validity of \pm 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.